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<b>INFORMATION DISCLOSURE STATEMENT BY APPLICANT</b>  (Use as many sheets as necessary)				<b>Complete If Known</b>	
				Application Number	10/784,786-Conf. #2218
				Filing Date	February 24, 2004
				First Named Inventor	Hasan Nejad
				Art Unit	2827
				Examiner Name	V. Q. Nguyen
Sheet	1	of	1	Attorney Docket Number	M4065.0509/P509 B

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Document Number Number-Kind Code <sup>2</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
✓	AA	US-2003/0223292	Dec., 2003	Nejad et al.	
✓	AB	US-5969380	Oct. 1999	Seyyedy	
✓	AC	US-6349054	Feb. 2002	Hidaka	
✓	AD	US-6373753	Apr., 2002	Proebsting	
✓	AE	US-6570795	May, 2003	Fricke et al.	
✓	AF	US-6577529	Jun., 2003	Sharma et al.	
✓	AG	US-6631085	Oct., 2003	Kleveland et al.	
✓	AH	US-6671213	Dec. 2003	Ohtani	
✓	AI	US-6680862	Jan., 2004	Hidaka	
✓	AJ	US-6680863	Jan., 2004	Shi et al.	
✓	AK	US-6693825	Feb., 2004	Sharma et al.	
✓	AL	US-6717222	Apr., 2004	Zhang	
✓	AM	US-6724653	Apr., 2004	Iwata et al.	
✓	AN	US-6756652	Jun., 2004	Yano et al.	
✓	AO	US-6778434	Aug., 2004	Tsuji	
✓	AP	US-6829188	Dec., 2004	Baker	
✓	AQ	US-6882553	Apr., 2005	Nejad et al.	

VIET Q. NGUYEN  
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FOREIGN PATENT DOCUMENTS					
Examiner Initials*	Cite No. <sup>1</sup>	Foreign Patent Document Country Code <sup>3</sup> -Number <sup>4</sup> -Kind Code <sup>5</sup> (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
✓	BA	JPO2002170376	Jun., 2002	Hidaka	
✓	BB	WO 000241321	May, 2002	Boehm et al.	

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NON PATENT LITERATURE DOCUMENTS			
Examiner Initials*	Cite No. <sup>1</sup>	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T <sup>2</sup>

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Examiner Signature	V. Nguyen	Date Considered	6/19/2005
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